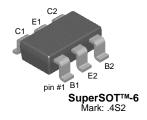


# FMBM5401 PNP General Purpose Amplifier

• This device has matched dies in SuperSOT-6.



## **Absolute Maximum Ratings\***

Symbol	Parameter	Value	Units	
V <sub>CEO</sub>	Collector-Emitter Voltage	-150	V	
V <sub>CBO</sub>	Collector-Base Voltage	-160	V	
$V_{EBO}$	Emitter-Base Voltage	-5.0	V	
I <sub>C</sub>	Collector Current - Continuous	-600	mA	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-55 ~ 150	°C	

 $<sup>^{\</sup>star}\,\text{These ratings are limiting values above which the serviceability of any semiconductor device may e impaired}.$ 

#### Notes:

## **Electrical Characteristics** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Conditions	Min.	Max	Units		
Off Charact	Off Characteristics						
BV <sub>CEO</sub>	Collector-Emitter Breakdown Voltage *	$I_C = -1.0 \text{mA}, I_B = 0$	-150		V		
BV <sub>CBO</sub>	Collector-Base Breakdown Voltage	$I_C = -100\mu A, I_E = 0$	-160		V		
BV <sub>EBO</sub>	Emitter-Base Breakdown Voltage	$I_C = -10\mu A, I_C = 0$	-5.0		V		
I <sub>CBO</sub>	Collector Cut-off Current	$V_{CB} = -120V, I_{E} = 0$ $V_{CB} = -120V, I_{E} = 0, T_{a} = 100^{\circ}C$		-50 -50	nA μA		
I <sub>EBO</sub>	Emitter Cut-off Current	$V_{EB} = -3.0V, I_{C} = 0$		-50	nA		
On Characteristics*							
h <sub>FE1</sub>	DC Current Gain	$V_{CE} = -5V$ , $I_{C} = -1mA$	50				
DIVID1	Variation Ratio of h <sub>FE1</sub> Between Die 1 and Die 2	h <sub>FE1</sub> (Die1)/h <sub>FE1</sub> (Die2)	0.9	1.1			
h <sub>FE2</sub>	DC Current Gain	$V_{CE} = -5V, I_{C} = -10mA$	60	240			
DIVID2	Variation Ratio of h <sub>FE2</sub> Between Die 1 and Die 2	h <sub>FE2</sub> (Die1)/h <sub>FE2</sub> (Die2)	0.95	1.05			
h <sub>FE3</sub>	DC Current Gain	$V_{CE} = -5V, I_{C} = -50mA$	50				
DIVID3	Variation Ratio of h <sub>FE3</sub> Between Die 1 and Die 2	h <sub>FE3</sub> (Die1)/h <sub>FE3</sub> (Die2)	0.9	1.1			

<sup>1.</sup> These ratings are based on a maximum junction temperature of 150 degrees  ${\sf C}.$ 

<sup>2.</sup> These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

## 

Symbol	Parameter	Conditions	Min.	Max	Units	
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	$I_C = -10mA, I_B = -1mA$ $I_C = -50mA, I_B = -5mA$	-0.2 -0.5	V V		
V <sub>BE(sat)</sub>	Base-Emitter Saturation Voltage	I <sub>C</sub> = -10mA, I <sub>B</sub> = -1mA I <sub>C</sub> = -50mA, I <sub>B</sub> = -5mA		-1 -1	V V	
V <sub>BE(on)</sub>	Base-Emitter On Voltage	$V_{CE} = -5V, I_{C} = -10mA$		-1	V	
DEL	Difference of V <sub>BE(on)</sub> Between Die1 and Die 2	V <sub>BE(on)</sub> (Die1)-V <sub>BE(on)</sub> (Die2)	-8	8	mV	
Small Signal Characteristics						
f <sub>T</sub>	Current Gain Bandwidth Product	$V_{CE} = -10V, I_{C} = -10mA$ f = 100MHz	100	300	MHz	
C <sub>ob</sub>	Output Capacitance	$V_{CB} = -10V, I_{E} = 0, f = 1MHz$		6.0	pF	
NF	Noise Figure	$V_{CE} = -5.0V$ , $I_{C} = -250\mu A$ , $R_{S} = 1.0K\Omega$ , $f = 10Hz$ to 15.7KHz		8.0	dB	

<sup>\*</sup> Pulse Test: Pulse Width  $\leq$  300ms, Duty Cycle  $\leq$  2.0%

## Thermal Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Value	Units	
P <sub>D</sub>	Total Device Dissipation	700	mW	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Total	180	°C/W	

<sup>\*</sup> Device mounted on a 1 in 2 pad of 2 oz coppe

## **Typical Performance Characteristics**

Figure 1. Typical Pulsed Current Gain vs Collector Current

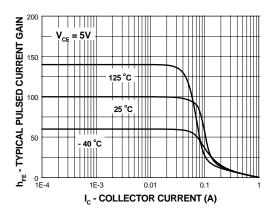


Figure 3. Base-Emitter Saturation Voltage vs Collector Current

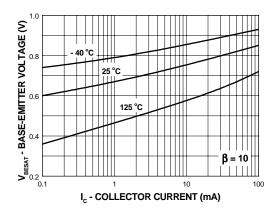


Figure 5. Collector-Cutoff Current vs Ambient Temperature

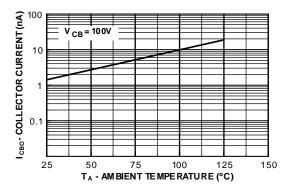


Figure 2. Collector-Emitter Saturation Voltage vs Collector Current

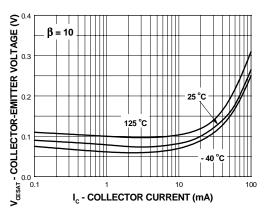


Figure 4. Base-Emitter On Voltage vs Collector Current

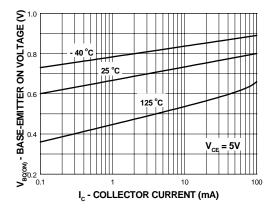
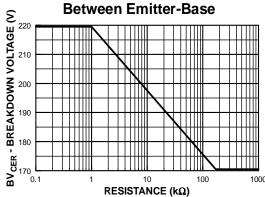


Figure 6. Collector-Emitter Breakdown Voltage with Resistance Between Emitter-Base

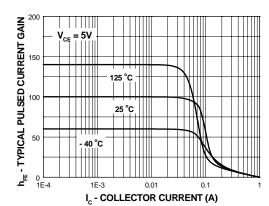


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## Typical Performance Characteristics (Continued)

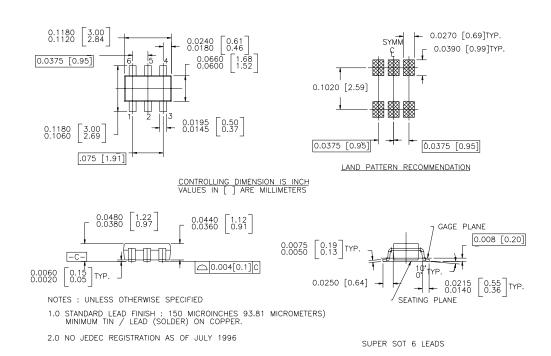
## Figure 7.Input and Output Capacitance vs Reverse Voltage



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### **Mechanical Dimensions**

## SuperSOT™-6



Dimensions in Millimeters

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E <sup>2</sup> CMOS™	I <sup>2</sup> C™	MSX™	QT Optoelectronics™	TinyLogic <sup>®</sup>
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FACT™	ImpliedDisconnect™	OCXTM	RapidConfigure™	TruTranslation™
FACT Quiet Series™		OCXPro™	RapidConnect™	UHC™
Across the board. Around the world.™		OPTOLOGIC <sup>®</sup>	μSerDes™	UltraFET <sup>®</sup>
The Power Franchise®		OPTOPLANAR™	SILENT SWITCHER®	UniFET™
Programmable Active Droop™		PACMAN™	SMART START™	VCX™
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